

February 1997

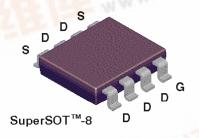
# NDH833N N-Channel Enhancement Mode Field Effect Transistor

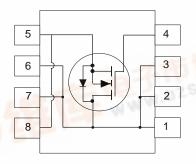
#### **General Description**

SuperSOT<sup>TM</sup>-8 N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as battery powered circuits or portable electronics where fast switching, low in-line power loss, and resistance to transients are needed.

### **Features**

- 7.1 A, 20 V.  $R_{DS(ON)} = 0.020~\Omega~@~V_{GS} = 4.5~V$   $R_{DS(ON)} = 0.025~\Omega~@~V_{GS} = 2.7~V.$
- Proprietary SuperSOT<sup>TM</sup>-8 package design using copper lead frame for superior thermal and electrical capabilities.
- High density cell design for extremely low R<sub>DS(ON)</sub>.
- Exceptional on-resistance and maximum DC current capability.





Absolute Maximum Ratings T<sub>A</sub> = 25°C unless otherwise note

Symbol	Parameter		NDH833N	Units
V <sub>DSS</sub>	Drain-Source Voltage		20	V
V <sub>GSS</sub>	Gate-Source Voltage		±8	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	7.1	Α
	- Pulsed		24	
P <sub>D</sub>	Maximum Power Dissipation	(Note 1a)	1.8	W
		(Note 1b)	1	
	CA TILLOGG	(Note 1c)	0.9	
T <sub>J</sub> ,T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to 150	°C
THERMA	L CHARACTERISTICS			
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	70	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	20	°C/W

Symbol	Parameter	Conditions	Min	Тур	Max	Units	
OFF CHA	RACTERISTICS						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		20			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 16 V, V <sub>GS</sub> = 0 V				1	μA
			T <sub>J</sub> = 55°C			10	μA
I <sub>GSSF</sub>	Gate - Body Leakage, Forward	$V_{GS} = 8 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I <sub>GSSR</sub>	Gate - Body Leakage, Reverse	$V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHAR	ACTERISTICS (Note 2)			•	•		•
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		0.4	0.62	1	V
			T <sub>J</sub> = 125°C	0.3	0.4	0.8	]
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS} = 4.5 \text{ V}, I_{D} = 7.1 \text{ A}$			0.015	0.02	Ω
			T <sub>J</sub> = 125°C		0.022	0.036	
		$V_{GS} = 2.7 \text{ V}, I_{D} = 6.7 \text{ A}$	$V_{GS} = 2.7 \text{ V}, I_{D} = 6.7 \text{ A}$				
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$		24			Α
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 7.1 \text{ A}$		35		S	
DYNAMIC	CHARACTERISTICS						
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 10 \text{ V}, \ V_{GS} = 0 \text{ V},$					pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz			750		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				265		pF
SWITCHIN	IG CHARACTERISTICS (Note 2)						
t <sub>D(on)</sub>	Turn - On Delay Time	$V_{DD} = 5 \text{ V}, I_D = 1 \text{ A},$			12	20	ns
t <sub>r</sub>	Turn - On Rise Time	$V_{GEN} = 4.5 \text{ V}, R_{GEN} = 6 \Omega$			35	70	ns
t <sub>D(off)</sub>	Turn - Off Delay Time				110	200	ns
t <sub>f</sub>	Turn - Off Fall Time				60	120	ns
$Q_g$	Total Gate Charge	$V_{DS} = 10 \text{ V},$			97	140	nC
$Q_{gs}$	Gate-Source Charge	$I_D = 7.1 \text{ A}, V_{GS} = 10 \text{ V}$			8		nC
$Q_{gd}$	Gate-Drain Charge				33		nC

<b>ELECTRICAL CHARACTERISTICS</b> (T <sub>A</sub> = 25°C unless otherwise noted)									
Symbol	Parameter Conditions Min Typ Max Units								
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS									
I <sub>s</sub>	Maximum Continuous Drain-Source Diode Forward Current 1.5 A								
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 1.5 A (Note 2)		0.65	1.2	V			

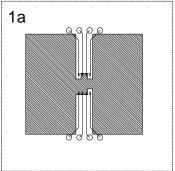
#### Notes

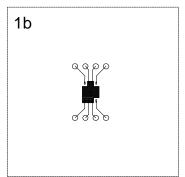
1. R<sub>gut</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>gut</sub> is guaranteed by design while R<sub>get</sub> is determined by the user's board design.

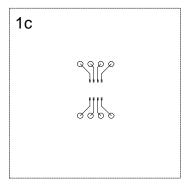
$$P_D(t) = \frac{T_{J^-}T_A}{R_{\theta J}A(t)} = \frac{T_{J^-}T_A}{R_{\theta J}d^*R_{\theta C}A(t)} = I_D^2(t) \times R_{DS(ON)@T_J}$$

Typical  $R_{\theta^{JA}}$  using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

- a. 70°C/W when mounted on a 1 in² pad of 2oz cpper.
- b. 125°C/W when mounted on a 0.026 in² pad of 2oz copper.
- c. 135°C/W when mounted on a 0.005 in² pad of 2oz copper.







Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width  $\leq 300 \mu s,$  Duty Cycle  $\leq 2.0 \%.$ 

# **Typical Electrical Characteristics**

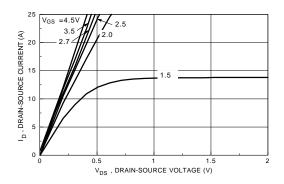


Figure 1. On-Region Characteristics.

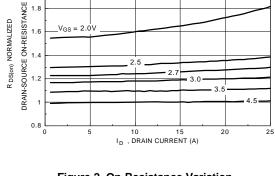


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

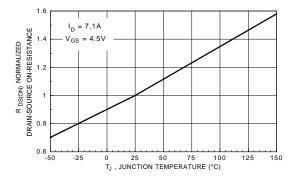


Figure 3. On-Resistance Variation with Temperature.

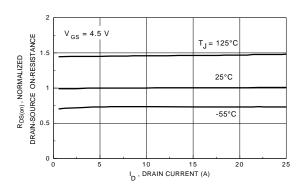


Figure 4. On-Resistance Variation with Drain Current and Temperature.

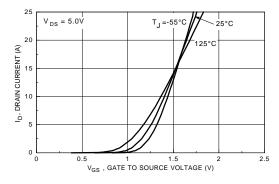


Figure 5. Transfer Characteristics.

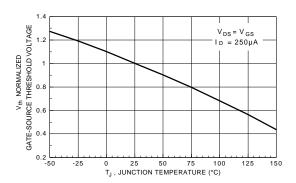


Figure 6. Gate Threshold Variation with Temperature.

# **Typical Electrical Characteristics (continued)**

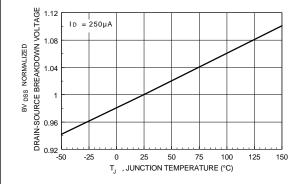


Figure 7. Breakdown Voltage Variation with Temperature.

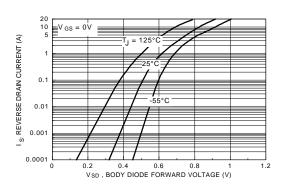


Figure 8. Body Diode Forward Voltage Variation with Source Current and Temperature.

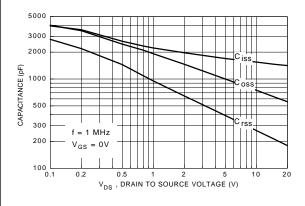


Figure 9. Capacitance Characteristics.

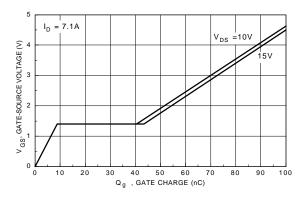


Figure 10. Gate Charge Characteristics.

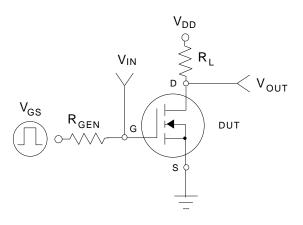


Figure 11. Switching Test Circuit.

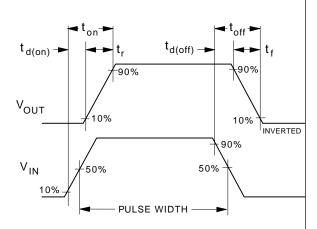


Figure 12. Switching Waveforms.

# Typical Electrical and Thermal Characteristics (continued)

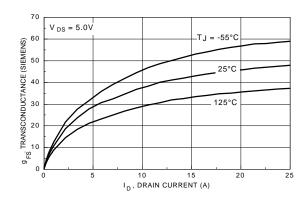
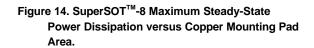
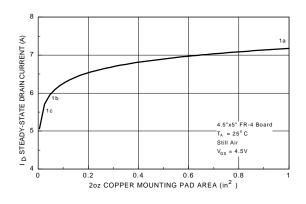


Figure 13. Transconductance Variation with Drain Current and Temperature.





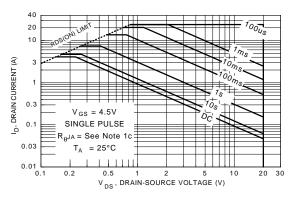


Figure 15. Maximum Steady-State Drain Current versus Copper Mounting Pad Area.

Figure 16. Maximum Safe Operating Area.

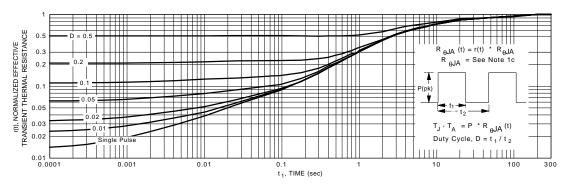
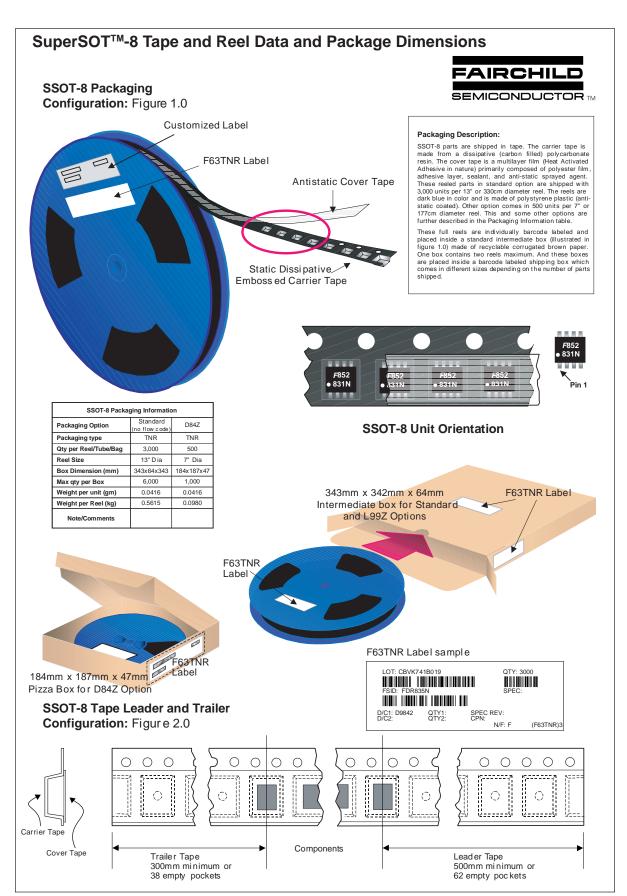
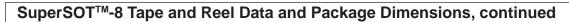


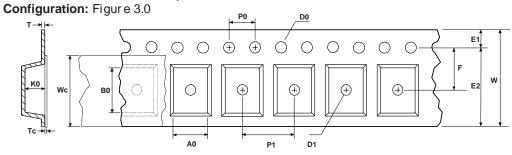
Figure 17. Transient Thermal Response Curve.

Note: Thermal characterization performed using the conditions described in note 1c. Transient thermal response will change depending on the circuit board design.





# **SSOT-8 Embossed Carrier Tape**



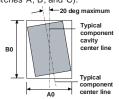
User Direction of Feed	
	$\overline{}$

	Dimensions are in millimeter													
Pkg type	A0	В0	w	D0	D1	E1	E2	F	P1	P0	K0	т	Wc	Тс
<b>SSOT-8</b> (12mm)	4.47 +/-0.10	5.00 +/-0.10	12.0 +/-0.3	1.55 +/-0.05	1.50 +/-0.10	1.75 +/-0.10	10.25 min	5.50 +/-0.05	8.0 +/-0.1	4.0 +/-0.1	1.37 +/-0.10	0.280 +/-0.150	9.5 +/-0.025	0.06 +/-0.02

Notes: A0, B0, and K0 dimensions are determined with respect to the EIA/Jedec RS-481 rotational and lateral movement requirements (see sketches A, B, and C).



Sketch A (Side or Front Sectional View)
Component Rotation



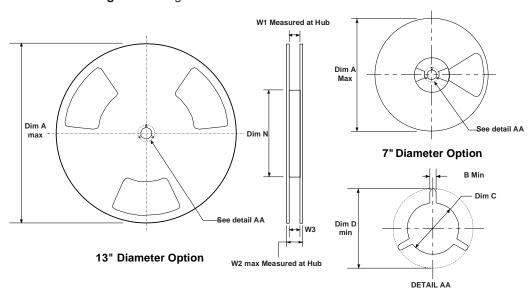
Sketch B (Top View)
Component Rotation



Sketch C (Top View)

Component lateral movement

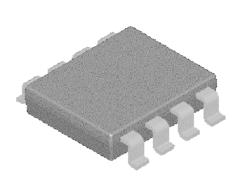
# SSOT-8 Reel Configuration: Figur e 4.0

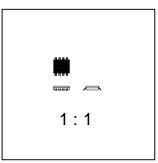


	Dimensions are in inches and millimeters								
Tape Size	Reel Option	Dim A	Dim B	Dim C	Dim D	Dim N	Dim W1	Dim W2	Dim W3 (LSL-USL)
12mm	7" Dia	7.00 177.8	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	5.906 150	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4
12mm	13" Dia	13.00 330	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	7.00 178	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4

# SuperSOT<sup>™</sup>-8 Tape and Reel Data and Package Dimensions, continued

# SuperSOT™-8 (FS PKG Code 34, 35)

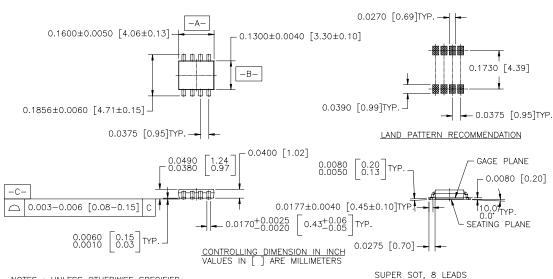




Scale 1:1 on letter size paper

Dimensions shown below are in: inches [millimeters]

Part Weight per unit (gram): 0.0416



NOTES: UNLESS OTHERWISE SPECIFIED

STANDARD LEAD FINISH TI BE 200 MICROINCHES / 5.08 MICROMETERS MINIMUM TIN/LEAD (SOLDER) ON COPPER.

2. NO JEDEC REGISTRATION AS JAN. 1996

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Datasheet Identification	Product Status	Definition
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No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
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